

# **Notice of References Cited**

Application/Control No.

10/055,278

Applicant(s)/Patent Under  
Reexamination  
BAWELL ET AL.

Examiner

Dean O Takaoka

Art Unit

2817

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## **U.S. PATENT DOCUMENTS**

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Boylestad, Introductory Circuit Analysis, Merrill, 4 <sup>th</sup> Edition, pages 227-230.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.